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| Notice of References Cited | Application/Control No. 09/917,054 | Applicant(s)/Patent Under Reexamination BATES ET AL. | |
| | Examiner Jean M Corrielus | Art Unit 2162 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-6,424,980 | 07-2002 | Iizuka et al. | 715/513 |
| | B | US-6,735,628 | 05-2004 | Eyal, Aviv | 709/223 |
| | C | US-6,397,218 | 05-2002 | Stern et al. | 707/10 |
| | D | US-6,643,641 | 11-2003 | Snyder, Russell | 707/4 |
| | E | US-6,647,383 | 11-2003 | August et al. | 707/3 |
| | F | US-6,594,694 | 07-2003 | Najork et al. | 709/219 |
| | G | US-6,480,853 | 11-2002 | Jain, Anuj Kumar | 707/10 |
| | H | US-6,466,940 | 10-2002 | Mills, Dudley John | 707/102 |
| | I | US-6,734,886 | 05-2004 | Hagan et al. | 715/853 |
| | J | US-6,389,467 | 05-2002 | Eyal, Aviv | 709/223 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | R | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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